

## Supplementary Information

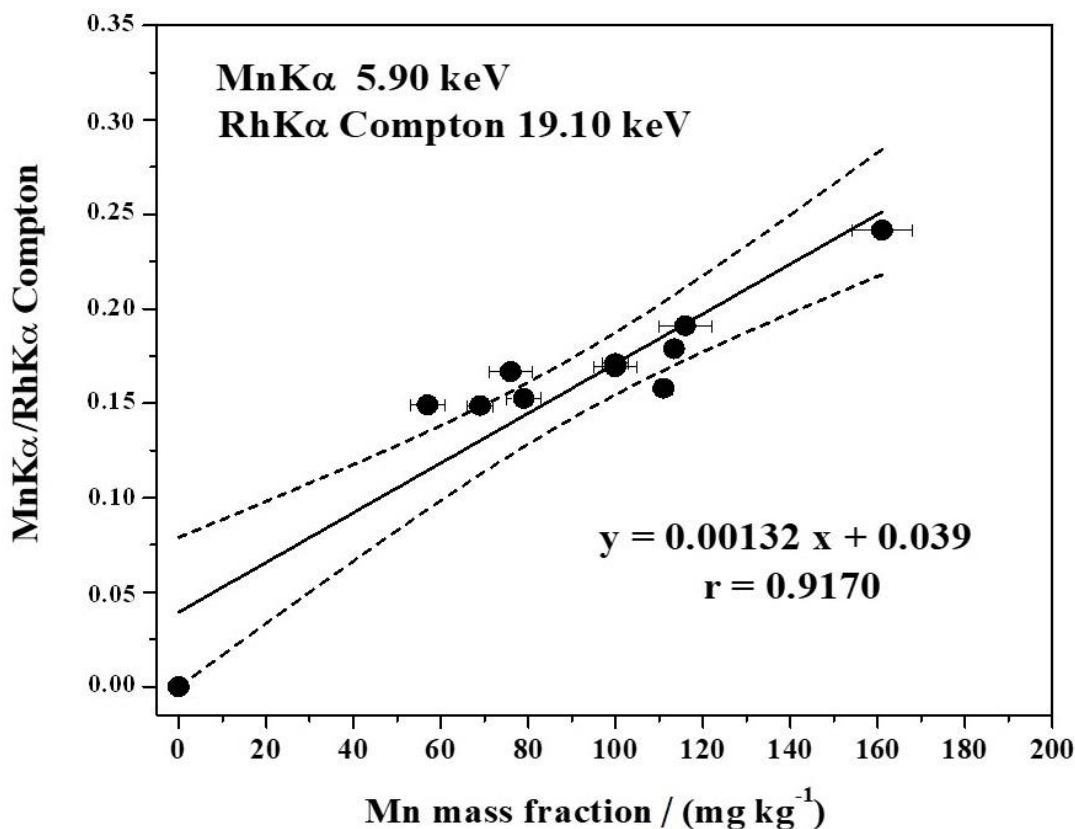
### *In situ* Determination of K, Ca, S and Si in Fresh Sugar Cane Leaves by Handheld Energy Dispersive X-Ray Fluorescence Spectrometry

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**Figure S1.** Analytical curve for Mn K $\alpha$  5.90 keV, obtained from the *in situ* analysis of fresh sugar cane leaves by a handheld EDXRF spectrometer. The Mn K $\alpha$  emission line intensities were corrected by the scattering radiation method using the Rh K $\alpha$  Compton peak at 19.10 keV. Dotted lines represent 95 % confidence bands.

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